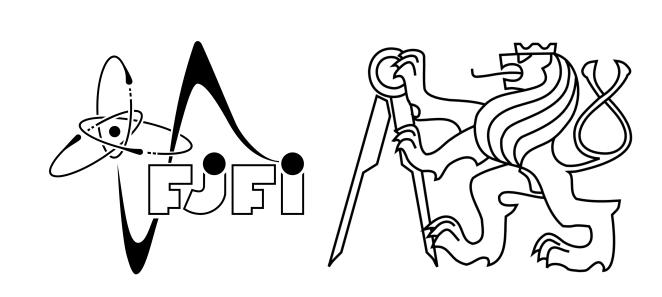
Commissioning of the Muon Forward Tracker for ALICE upgrade čssvk2020

ALICE

Diana Krupova Czech Technical University September 18, 2020

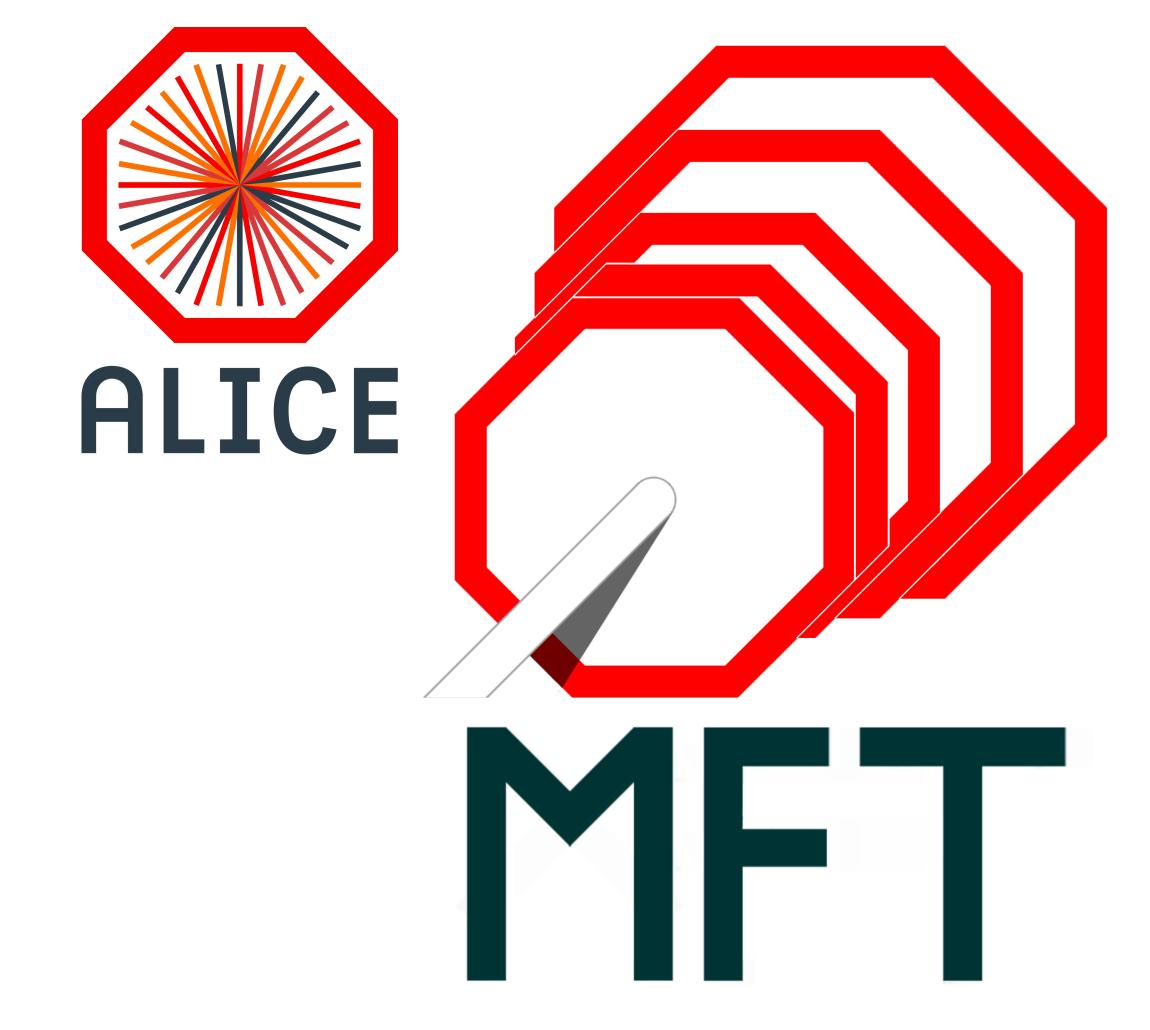


Outline

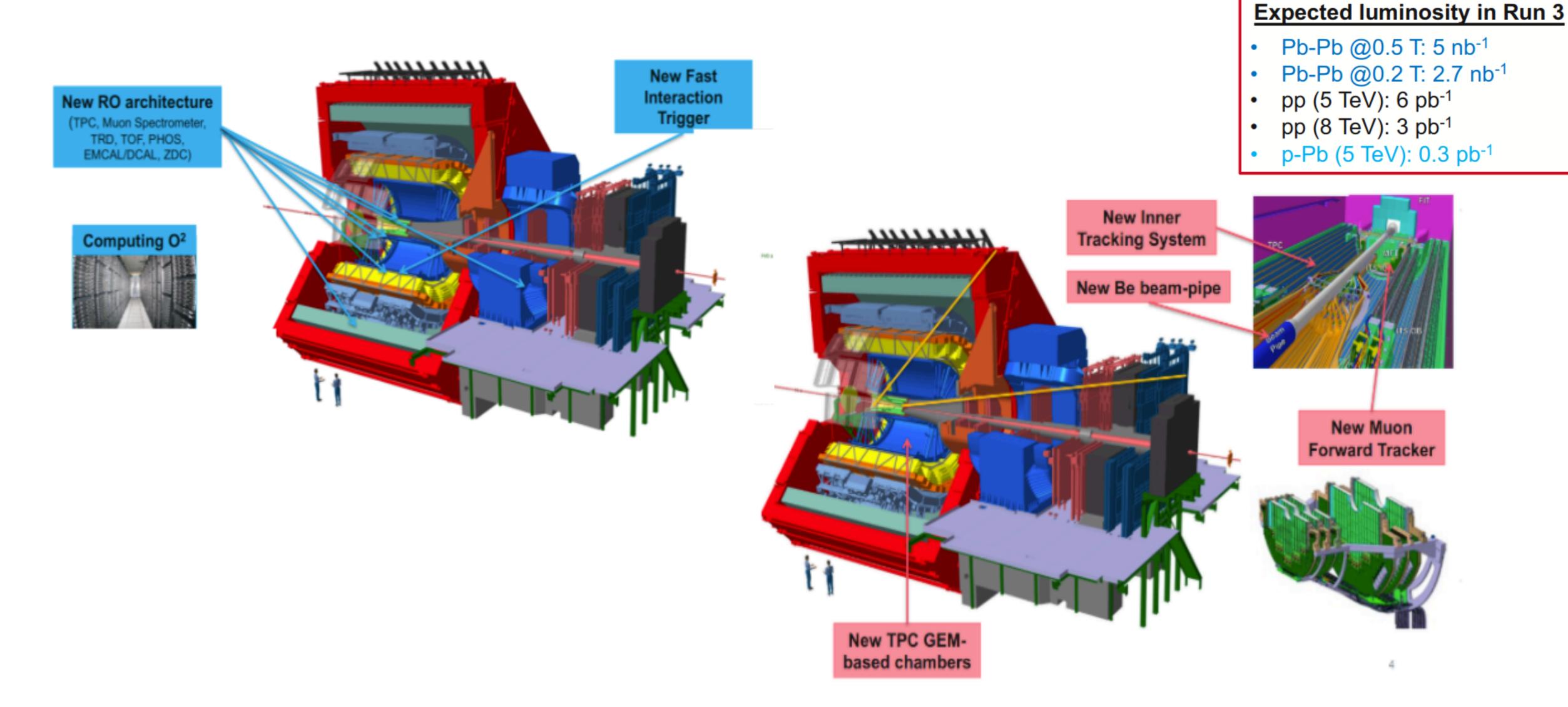
- ALICE upgrade for Run 3
- the Muon Forward Tracker and the ALPIDE pixel chips

MFT commissioning:

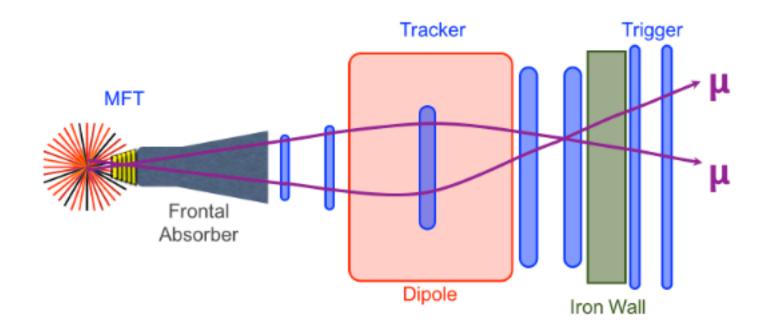
- ladder assembly
- ladder testing
- ladder qualification analysis test

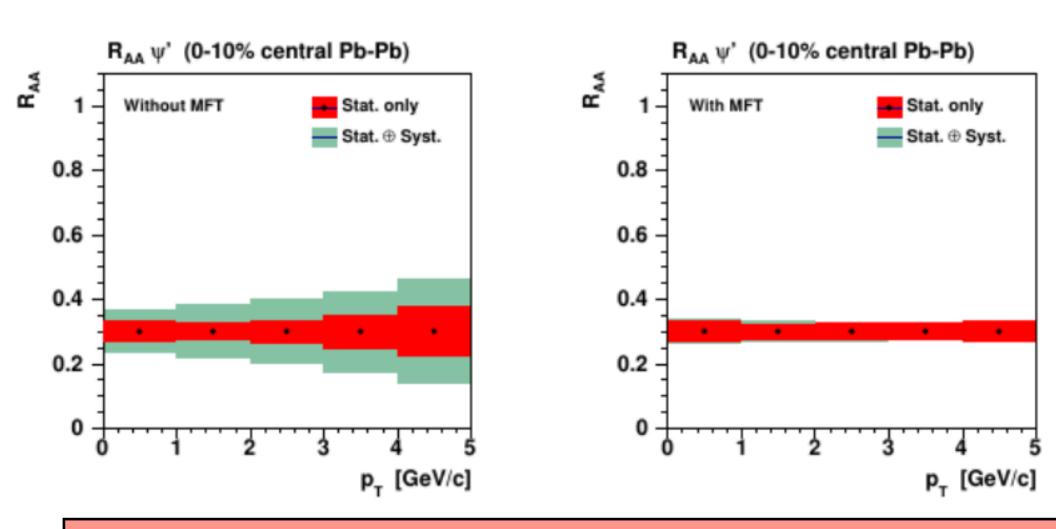


ALICE upgrade during the Long Shutdown 2

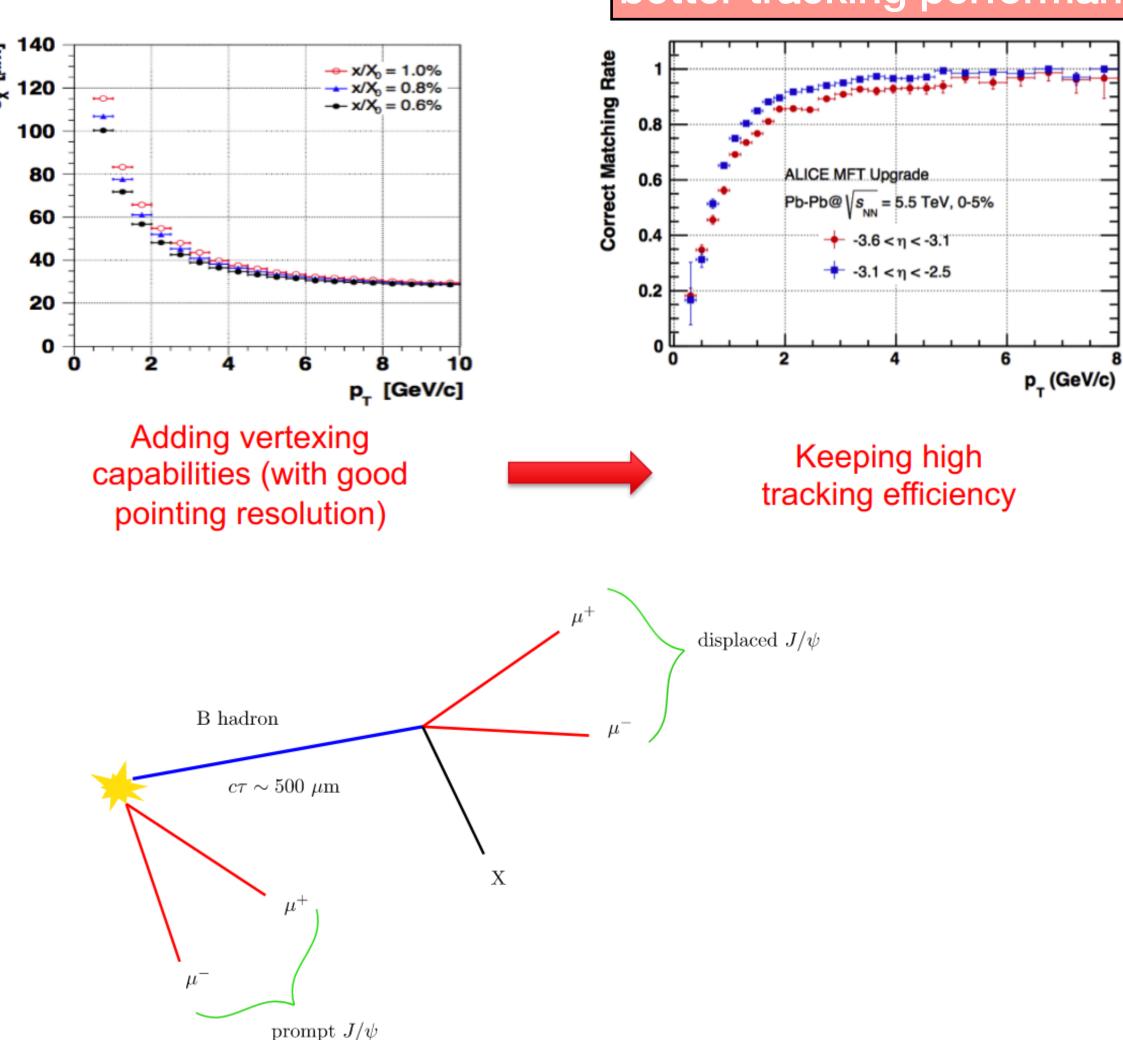


Physics motivation to build the MFT better tracking performance





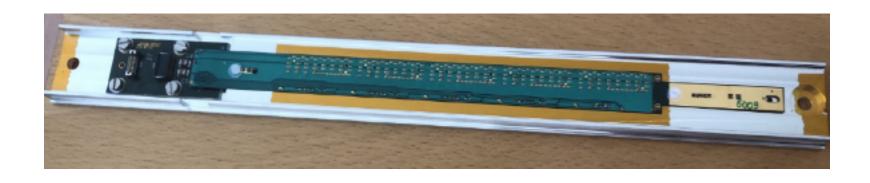
significantly reduced uncertainties of R_{AA} of the ψ'



separation of prompt and displaced J/ψ

Muon Forward Tracker (MFT)

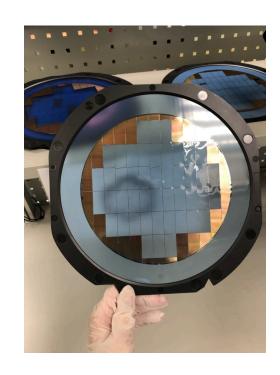
adds precise vertexing capabilities to muon tracking at forward rapidites



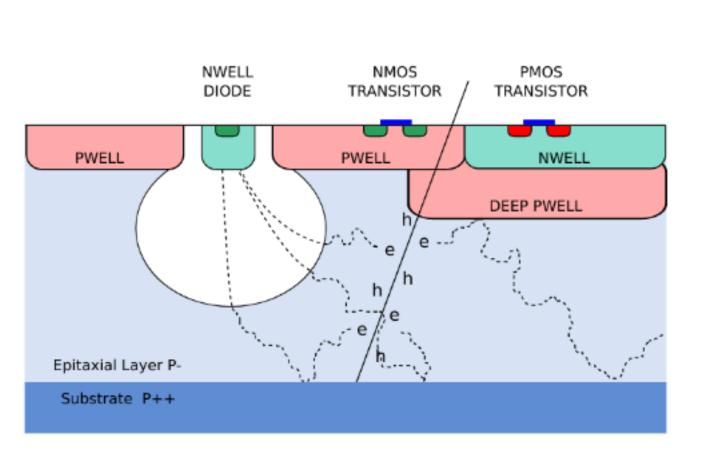
ALPIDE pixel sensor

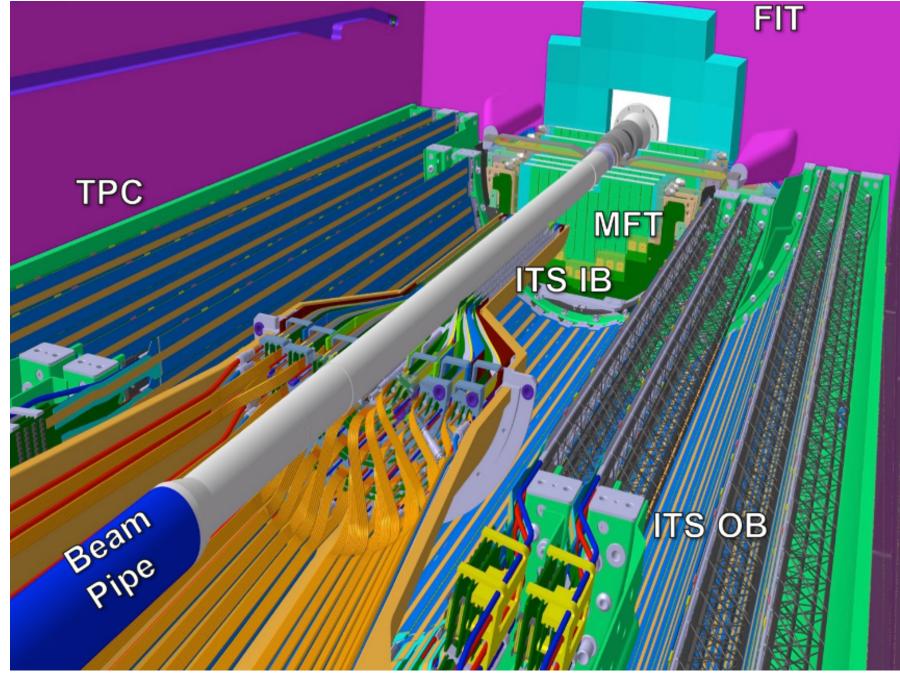
920 silicon pixel sensors (0.4 m²) on 280 ladders of 2 to 5 sensors each

CMOS Monolithic Active Sensor (MAPS), TowerJazz 180 nm technology

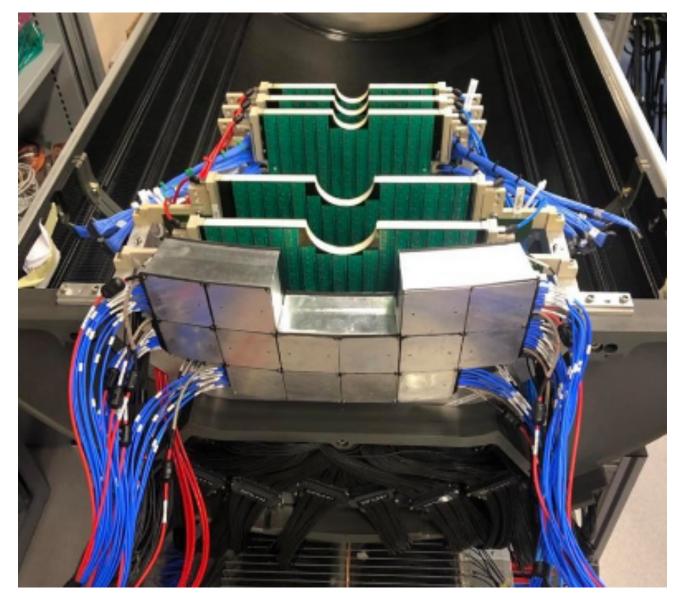


- developed for the ITS and the MFT
- ullet thickness 50 μ m
- 130 000 pixels/m²
- event-time resolution: <4 μ s
- space resolution: 5 μ m





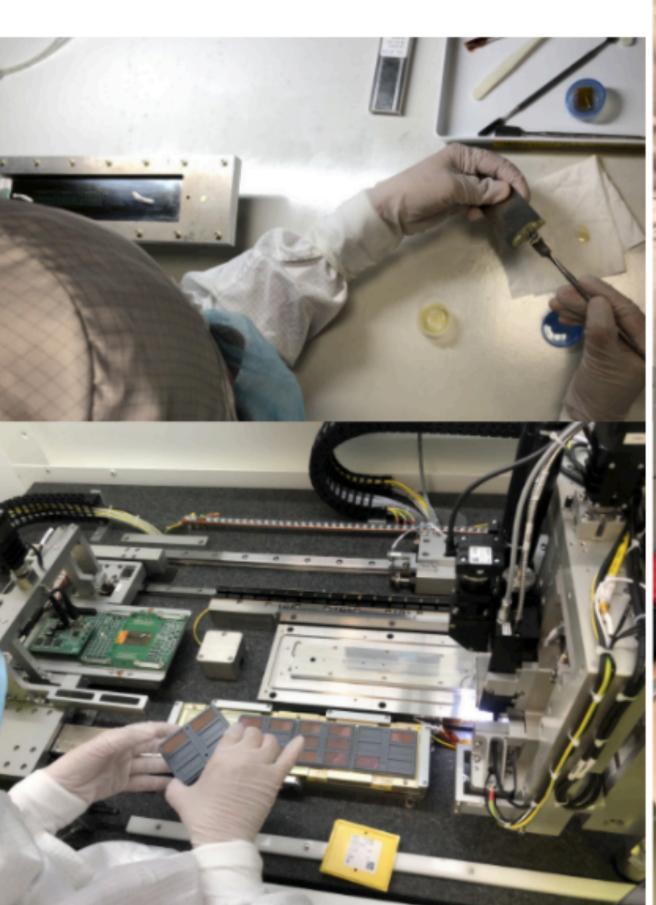
10 half-disks, 2 detection planes each



Commissioning

Ladders assembly

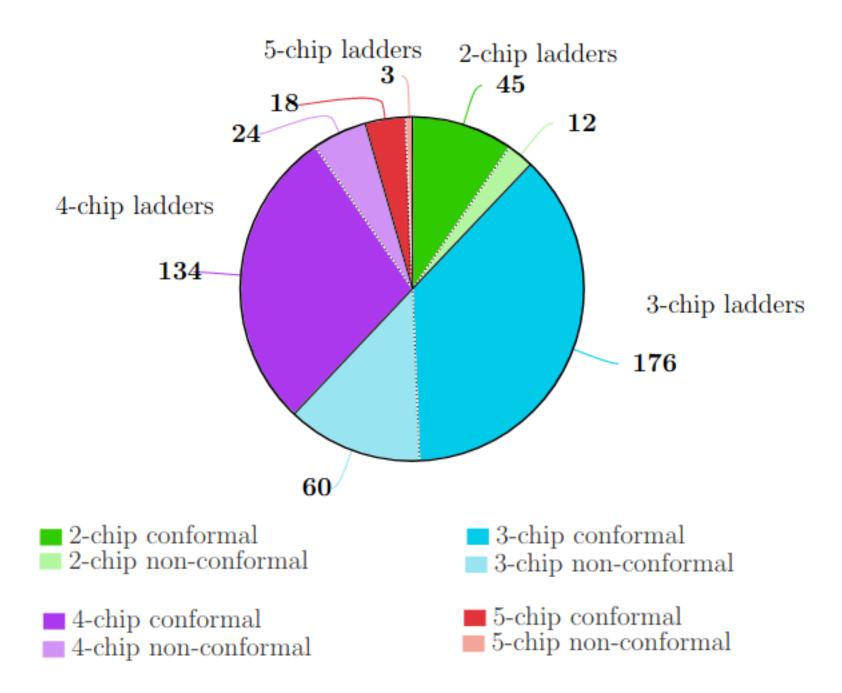


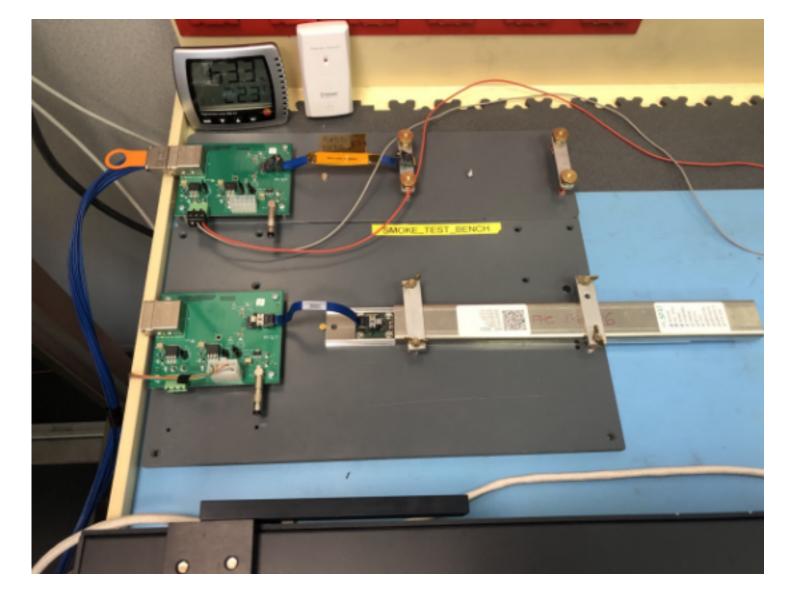


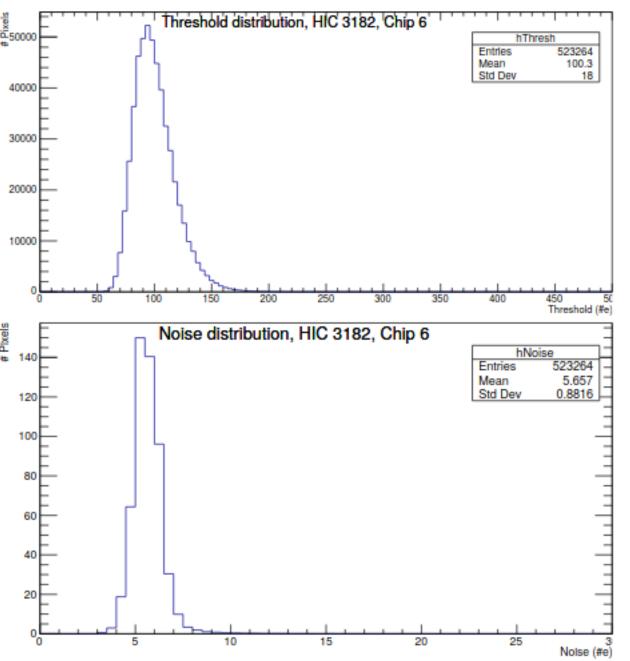


Commissioning: Ladder quality assurance

- several stages
- performed at CERN for all the ladders after the assembly, before gluing them to the disks
- results stored in an online database





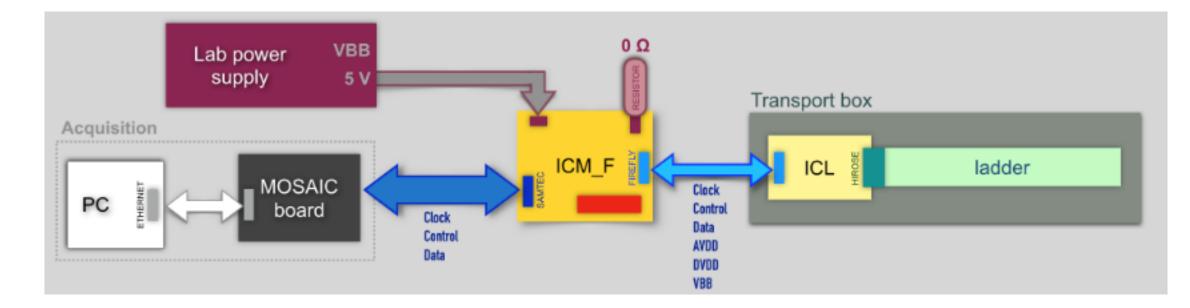


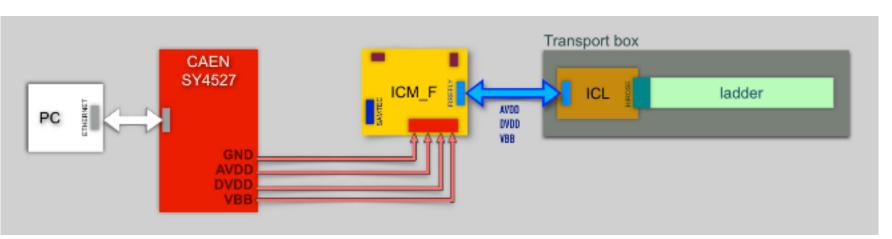
Qualification tests

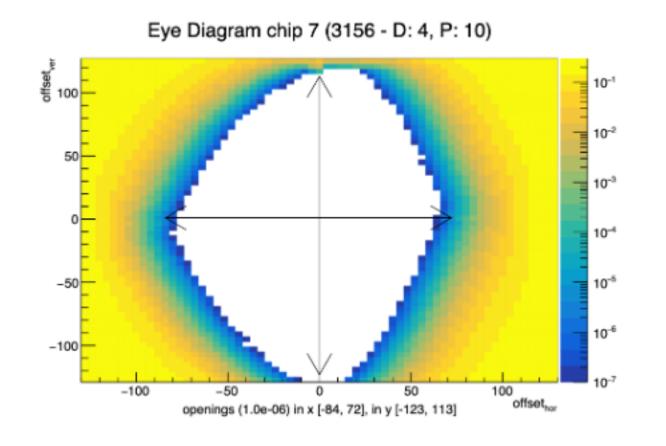
smoke test

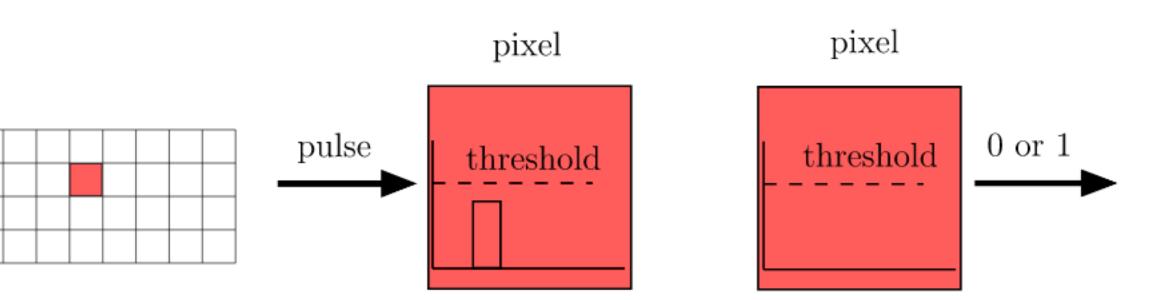
both with and without back-bias voltage (-3 V):

- readout test
- FIFO scan
- digital scan: dead, inefficient and noisy pixels
- threshold tests
- noise occupancy
- eye diagram: output signal strength and stability





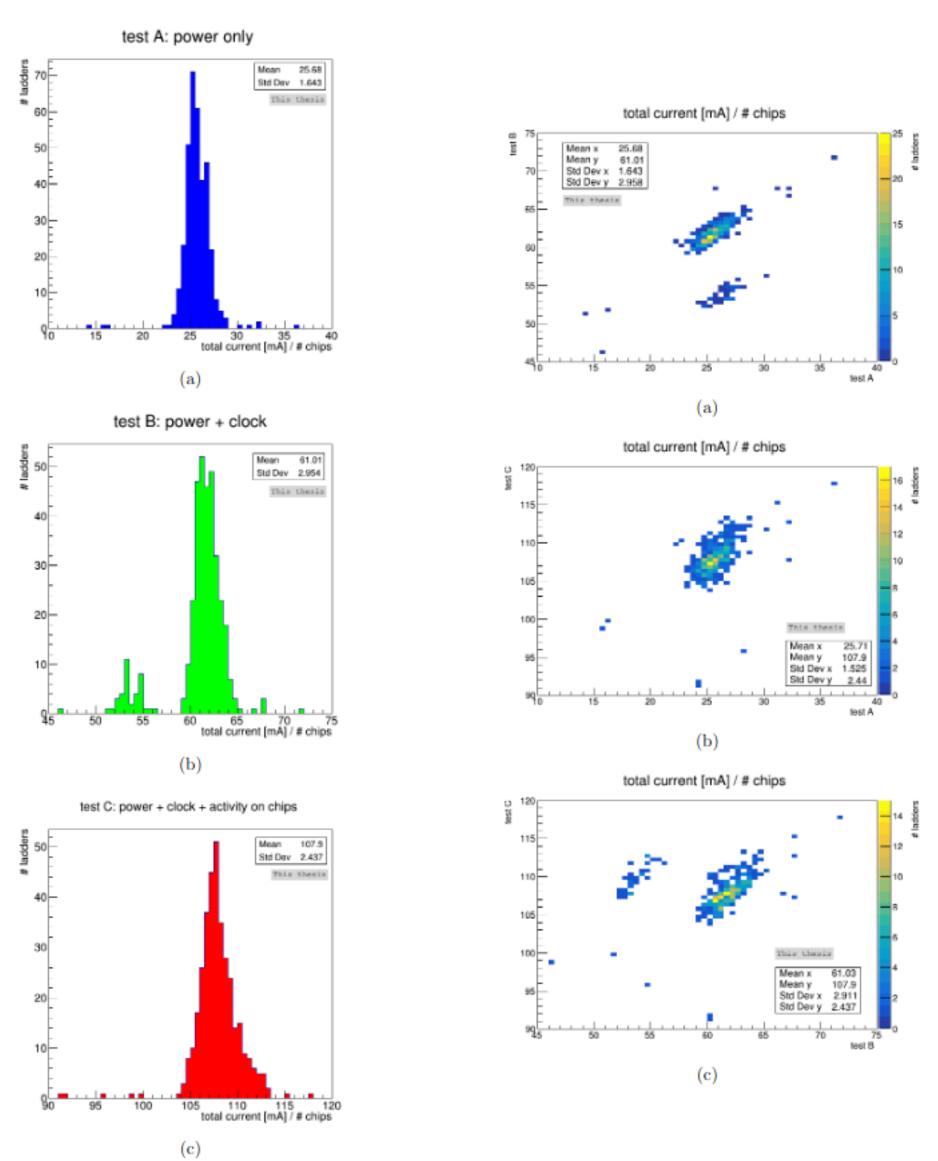






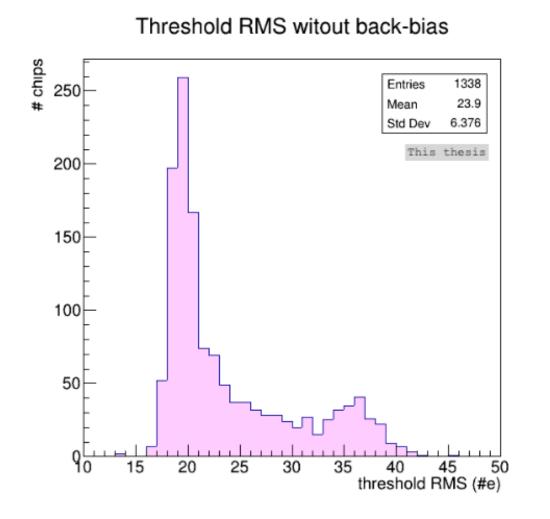
to describe the characteristic of the detector after subjecting the chips to various qualification tests

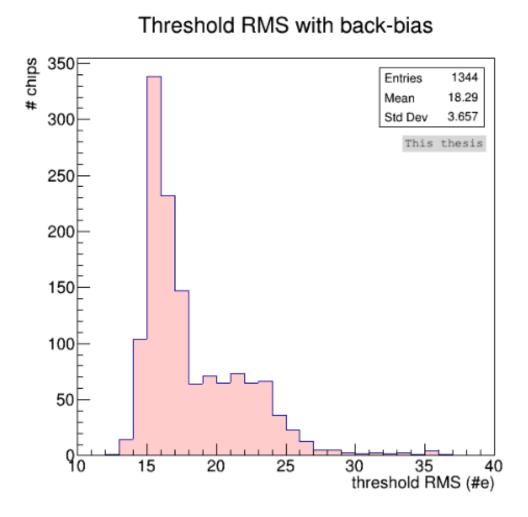
- power consumption + correlations
- threshold and noise characteristics
- dead, noisy and inefficient pixels
- VCASN values

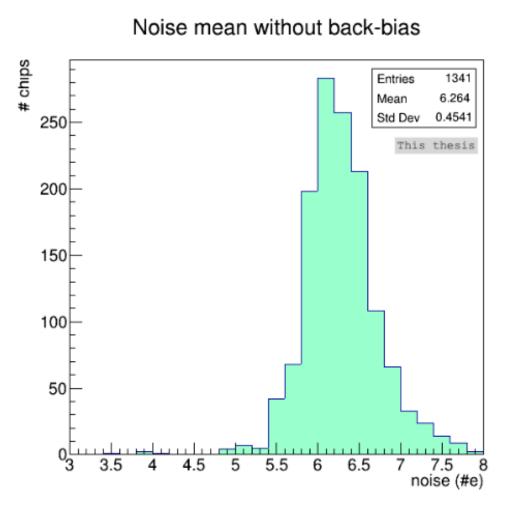


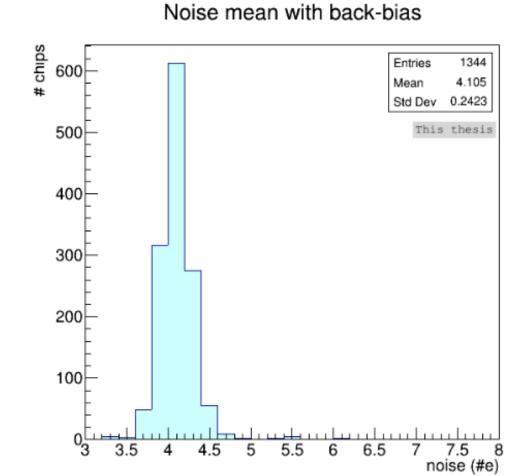
to describe the characteristic of the detector after subjecting the chips to various qualification tests

- power consumption + correlations
- threshold and noise characteristics
- dead, noisy and inefficient pixels
- VCASN values





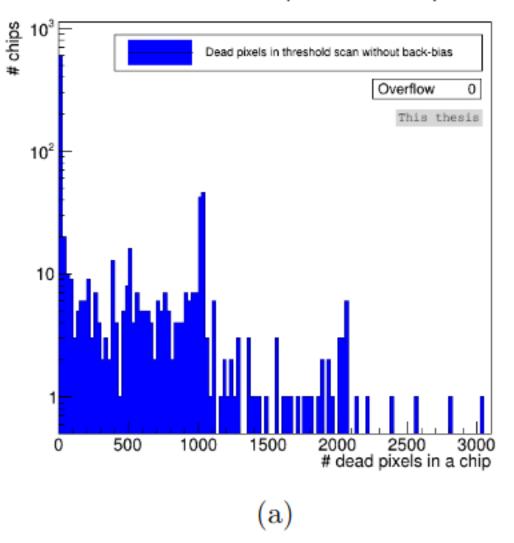




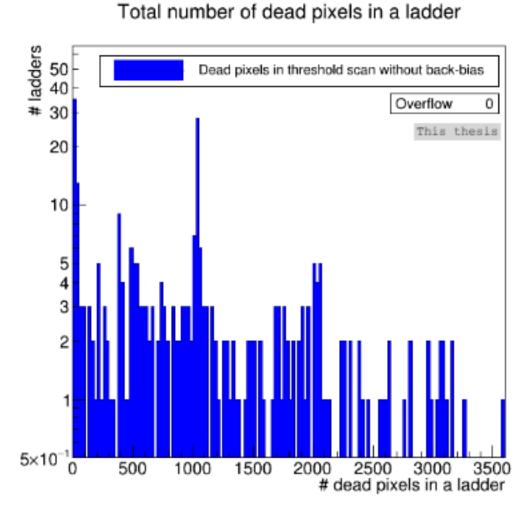
to describe the characteristic of the detector after subjecting the chips to various qualification tests

- power consumption + correlations
- threshold and noise characteristics
- dead, noisy and inefficient pixels
- VCASN values

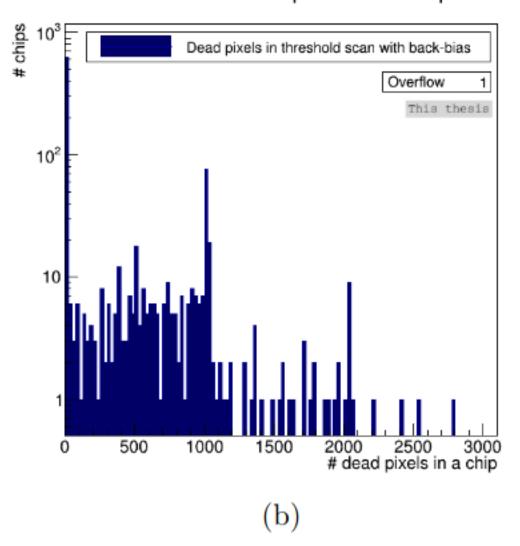
Number of dead pixels in a chip



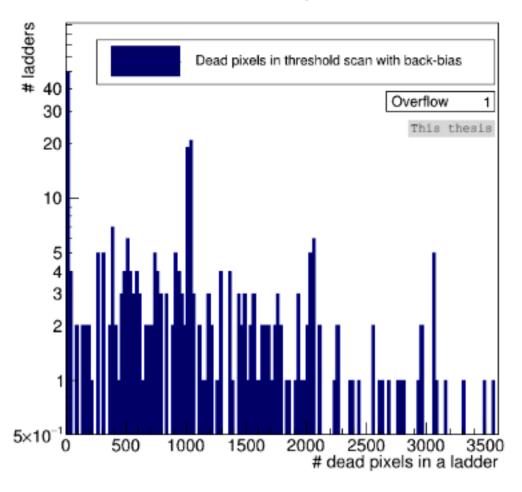
Sakal according of alamata basels to a landalac



Number of dead pixels in a chip



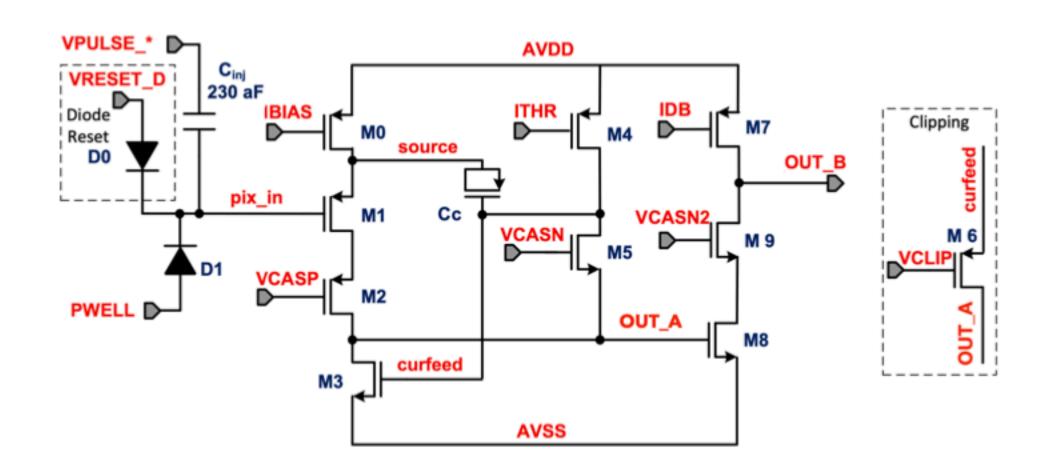
Total number of dead pixels in a ladder



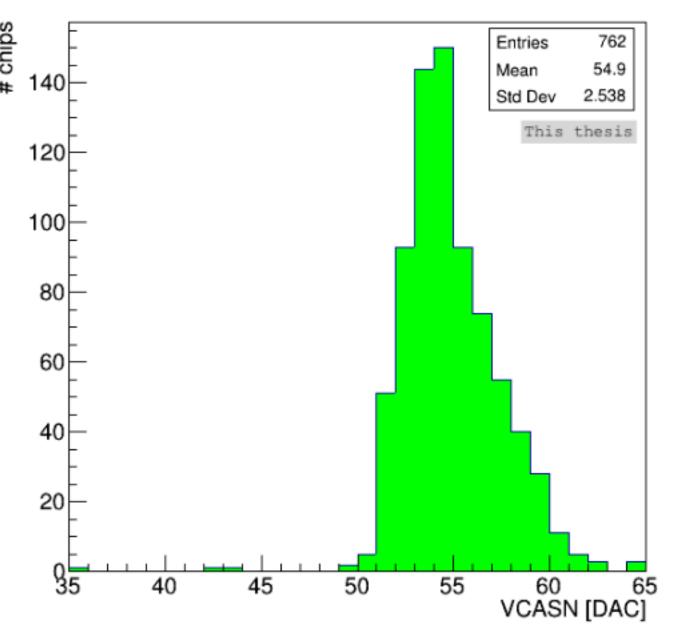
(c) (d)

to describe the characteristic of the detector after subjecting the chips to various qualification tests

- power consumption + correlations
- threshold and noise characteristics
- dead, noisy and inefficient pixels
- VCASN values



Average VCASN without back-bias



Average VCASN with back-bias

